

<b>Notice of References Cited</b>	Application/Control No. 10/042,573	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner Michelle Estrada	Art Unit 2823	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,391,768	05-2002	Lee et al.	438/633
	B	US-6,528,341	03-2003	Schiavone et al.	438/72
	C	US-6,503,828	01-2003	Nagahara et al.	438/633
	D	US-6,376,361	04-2002	Chooi et al.	438/631
	E	US-6,022,751	02-2000	Shindo et al.	438/21
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Chiang et al., US Patent Application Publication US 2003/0073286 A1, Pub. Date: April 17, 2003.
	V	Yokoi et al., US Patent Application Publication US 2003/0003754 A1, Pub. Date: January 2, 2003.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.